Technical **Publication TP202P**

Issue 1 November 1984

Inverter Grade Stud-Base Thyristor Type P202P 175 amperes average: up to 1200 volts V_{RRM}/V_{DRM}

Ratings (Maximum values at 125°C Tj unless stated otherwise)

RATING	CONDITIONS	SYMBOL		
Average on-state current R.M.S. on-state current Continuous on-state current	Half sine wave 85°C case temperature	H _(AV) H _(RMS)	175 A 355 A 355 A	
Peak one-cycle surge (non-repetitive) on state current	10ms duration, 60% V_{RRM} re-applied 10ms duration, $V_{R} \le 10$ volts	TSM (1)	3250 A 3575 A	
Maximum permissible surge energy	10ms duration, $V_R \le 10 \text{ volts}$ 3ms duration, $V_R \le 10 \text{ volts}$	i²t (2)	63900 A ² s 47000 A ² s	
Peak forward gate current	Anode positive with respect to cathode	I _{FGM}	18 A	
Peak forward gate voltage	Anode positive with respect to cathode	V _{EGM}	12 V	
Peak reverse gate voltage		V _{RGM}	5 V	
Average gate power		P _G	1.5 W	
Peak gate power	100μs. pulse width	P _{GM}	60 W	
Rate of rise of off-state voltage	To 80% V _{DRM} gate open-circuit	dv/dt	*200 V/μs	
Rate of rise of on-state current (repetitive)	Gate drive 20 volts, 20 ohms with $t_i \le 1\mu s$.	di/dt (1)	500 A/μs	
Rate of rise of on-state current (non-repetitive)	Anode voltage ≤ 80% V _{DRM}	di/dt (2)	1000 A/μs	
Operating temperature range		T _{CASE}	- 40 + 125°C	
Storage temperature range	,	T _{sta}	-40 + 150°C	

Characteristics (Maximum values at 125°C Tj unless stated otherwise)

CHARACTERISTIC	CONDITIONS						OL		
Peak on-state voltage	At 600 A, I _{TM}							2.074 V	
Forward conduction threshold voltag	e		****				V _{TM} V _O	1	1.55 V
Forward conduction slope resistance							r		$0.87~\mathrm{m}\Omega$
Repetitive peak off-state current		At V _{DRM}					IDRM		30 mA
Repetitive peak reverse current		At V _{RRM}					IRRM		30 mA
Maximum gate current required to fir)				,	I _{GT}	į	200 mA
Maximum gate voltage required to fir	e all devices	At 25°0	$V_{A} = 6$	$V, I_{\Delta} = 1$	4)	V _{GT}	1	3 V
Maximum holding current)	•			(4		600 mA
Maximum gate voltage which will no any device	t trigger						v _{GD}		0.25 V
Stored charge	1.	$T_{M} = 300 \text{ A}$ $V_{BM} = 50 \text{ V}$, dir/dt 2	0 A/μs			Q _{rr} typi	cal	45 μC
Circuit commutated turn-off time available down to		$I_{TM} = 300 \text{ A}$ $\begin{cases} 200 \text{V}/\mu\text{s to } 80\% \text{ V}_{DRM} \\ \text{dir/dt} = 20 \text{A}/\mu\text{s}, \text{V}_{RM} = 50 \text{V} \end{cases}$ $\begin{cases} 200 \text{V}/\mu\text{s to } 80\% \text{ V}_{DRM} \\ 20 \text{V}/\mu\text{s to } 80\% \text{ V}_{DRM} \end{cases}$					tq tq typi	cal	25-40 μs 15-35 μs
Thermal resistance, junction to case for a device with a maximum forward drop characteristic		DHM					R _{th(j-c)}		15–35 µs 0.12°C/W
VOLTAGE CODE		H02	H03	H04	H06	H08	H10	H12	
Repetitive peak voltages	V V	1		ļ	<u> </u>		1	-	-

VOLTAGE CODE		H02	H03	H04	H06	H08	H10	H12	
Repetitive peak voltages Non-repetitive peak off-state voltage	V _{RRM} V _{DRM} V _{DSM}	200	300	400	600	800	1000	1200	
Non-repetitive peak reverse blocking	voltage V _{RSM}	300	400	500	700	900	1100	1300	

Ordering Information (Please quote device code as explained below)

P 2 0 2 P	• • •	•	•	0	
Fixed type code	Voltage Code (see ratings)	dv/dt code to 80% V_{DRM} C = 20V/ μ s E = 100V/ μ s D = 50V/ μ s F = 200V/ μ s	Turn-o 2K = 40 μs H = 30 μs K = 20 μs	off time G = 35 μs J = 25 μs L = 15 μs	

Typical code: P202PH08FJ0 = 800 V_{RRM} 800 V_{DRM} 200 $V/\mu s$ dv/dt to 80% V_{DRM} 25 μs turn-off

^{*}Other values of dv/dt up to 1000 $V/\mu s$, and turn-off time may be available.

1. INTRODUCTION

The P202P thyristor series are diffused regenerative gate devices employing a 24 mm slice in a stud based top-hat housing.

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2. NOTES ON THE RATINGS

(a) Rate of rise of on-state current

The maximum un-primed rate of rise of on-state current must not exceed 1000 A/ μ s at any time during turn-on on a non-repetitive basis. For repetitive performance the on-state rate of rise of current must not exceed 500 A/ μ s at any time during turn-on. Note that these values of current rate of rise apply to the circuit external to the device and its specified snubber network and device current rates of rise will be higher.

(b) Square wave ratings

These ratings are given for leading edge linear rates of rise of forward current of 100 and 500 A/ μ s.

(c) Duty Cycle Lines

The 100% duty cycle line appears on all these ratings. These frequency ratings are presented in the form that all duty cycles may be represented by straight parallel lines.

(d) Maximum operating Frequency

The maximum operating frequency, f_{max}, is set by the time required for the thyristor to turn off (tq) and for the off-state voltage to reach full value (tv), i.e.

$$f_{\text{max}} = \frac{1}{t_{\text{pulse}} + tq + tv}$$

(e) Energy per pulse characteristics

These curves enable rapid estimation of device dissipation to be obtained for conditions not covered by the frequency ratings.

Let $\mathbf{E}_{\mathbf{p}}$ be the Energy per pulse for a given current and pulse width, in joules.

Then $W_{AV} = E_p \times f$.

3. REVERSE RECOVERY LOSS

On account of the number of circuit variables affecting reverse recovery voltage, no allowance for reverse recovery loss has been made in these ratings. The following procedure is recommended for use where it is necessary to include reverse recovery loss.

(a) Determination by Measurement

From waveforms of recovery current obtained from a high frequency shunt (see Note 1) and reverse voltage present during recovery, an instantaneous reverse recovery loss waveform must be constructed. Let the area under this waveform be A joules per pulse. A new case temperature can then be evaluated from:

$$T_{CASE}$$
 (new) = T_{CASE} (original) - $A\left(\frac{r_t \cdot 10^6}{t} + R_{th} \times f\right)$

where $r_t = 1.64 \times 10^{-4} \sqrt{t}$

t = duration of reverse recovery loss per pulse in microseconds

A = Area under reverse loss waveform per pulse in joules (W.S.)

f = rated frequency at the original case temperature The total dissipation is now given by

 $W_{(TOT)} = W_{(original)} + A \times f$

(b) Design Method

In circumstances where it is not possible to measure voltage and current conditions, or for design purposes, the additional losses may be estimated from figure 7. A typical R-C snubber network is connected across the thyristor to control the transient reverse voltage waveform.

Let E be the value of energy per reverse cycle in joules (figure 7).

Let f be the operating frequency in Hz

then T_{CASE} new = T_{CASE} original – $ER_{th} \times f$

where T_{CASE} new is the required maximum case temperature

and T_{CASE} original is the case temperature given with the frequency ratings.

4. GATE DRIVE

The recommended gate drive is 20 V, 20 ohms with a short-circuit current rise time of not more than 1 μ s. This gate drive must be applied when using the full di/dt capability of the device.

5. THE DV/DT SUPPRESSION NETWORK

The effect of a conventional resistor-capacitor snubber of 0.22 μ F 22 ohms has been included in these ratings and all rating di/dt values apply to the circuit external to the thyristor and its suppression network.

Snubber Network Values

A series connected C-R filter may be required across the anode to cathode terminals of the thyristor for the purpose of reducing off-state voltage overshoot.

The optimum values for C and R depend partly on the circuits connected to the thyristor. For most applications the snubber design values should not exceed a maximum of 0.22 μ F or a minimum of 22 ohms. Please consult Westcode for values outside these limits.

6. NOTE 1

REVERSE RECOVERY LOSS BY MEASUREMENT

This thyristor has a low reverse recovered charge and peak reverse recovery current. When measuring the charge care must be taken to ensure that:

- (a) a.c. coupled devices such as current transformers are not affected by prior passage of high amplitude forward current.
- (b) The measuring oscilloscope has adequate dynamic range — typically 100 screen heights to cope with the initial forward current without overload.

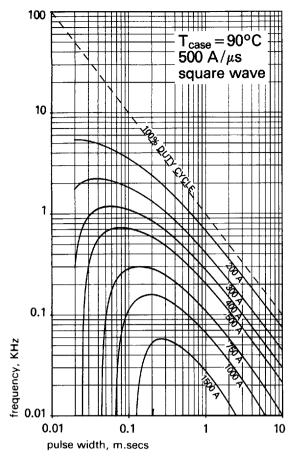


Figure 1 Frequency v. pulse width

Figure 2 Frequency v. pulse width

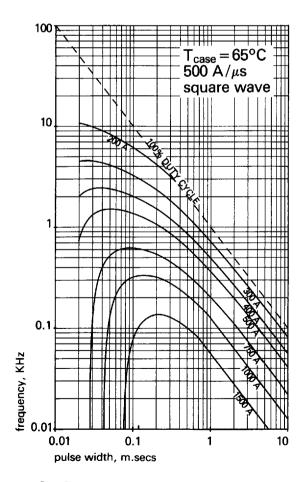


Figure 3 Frequency v. pulse width

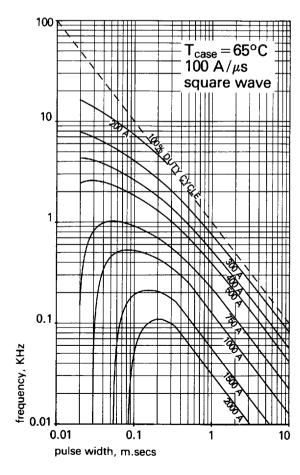
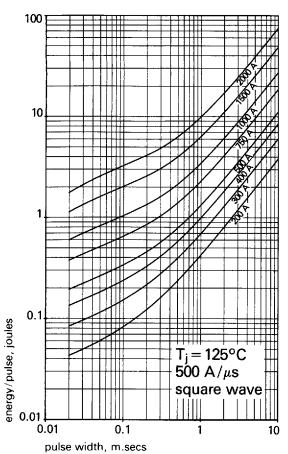


Figure 4 Frequency v. pulse width



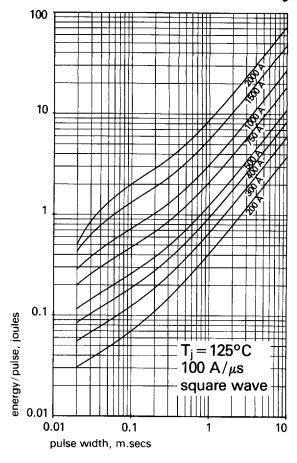


Figure 5 Energy/pulse v. pulse width

Energy/pulse v. pulse Figure 6 width

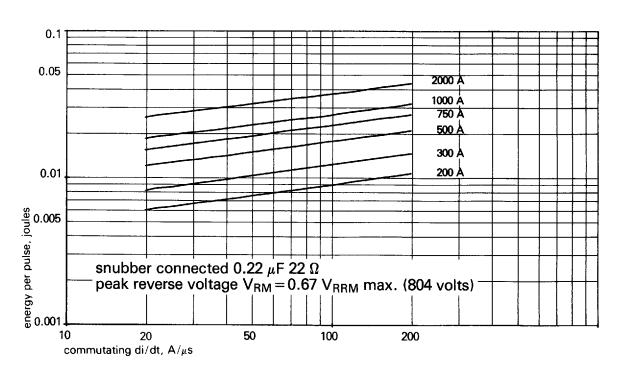


Figure 7 Max. reverse recovery energy loss per pulse at 125°C junction temperature and $V_{RM} = 804$ volts.

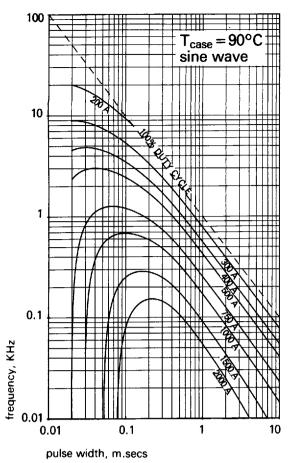


Figure 8 Frequency v. pulse width

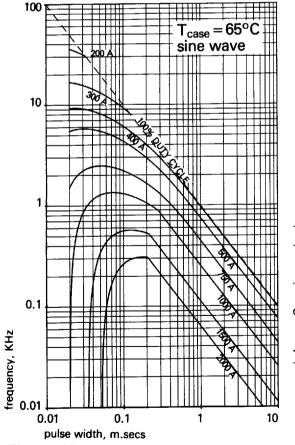


Figure 10 Frequency v. pulse width

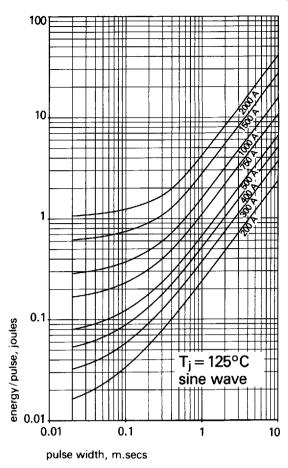


Figure 9 Energy/pulse v. pulse width

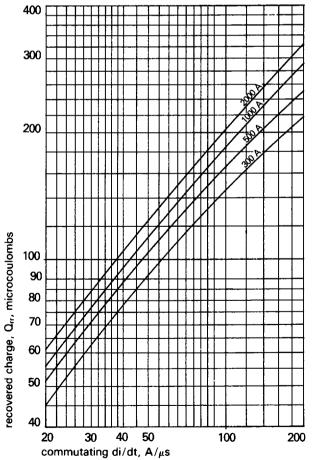
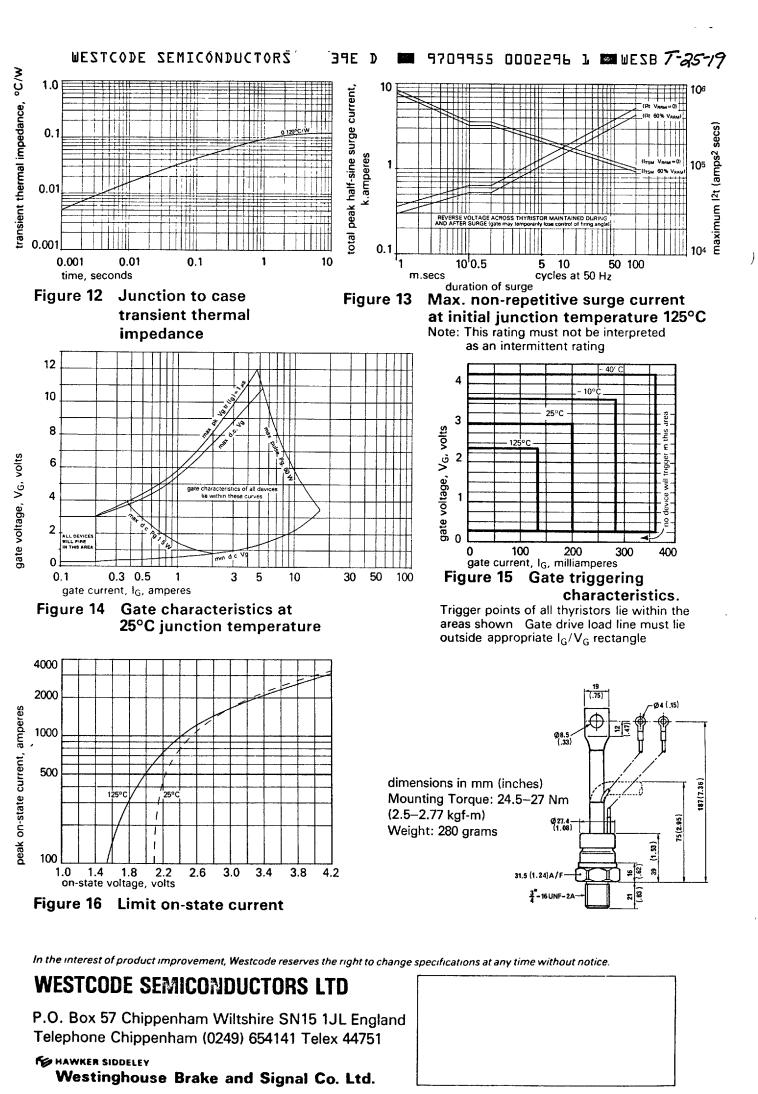


Figure 11 Typical recovered charge at 125°C junction temperature

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